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Details	
Product Status	Active
Number of LABs/CLBs	516
Number of Logic Elements/Cells	8256
Total RAM Bits	165888
Number of I/O	138
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2c8q208c8n

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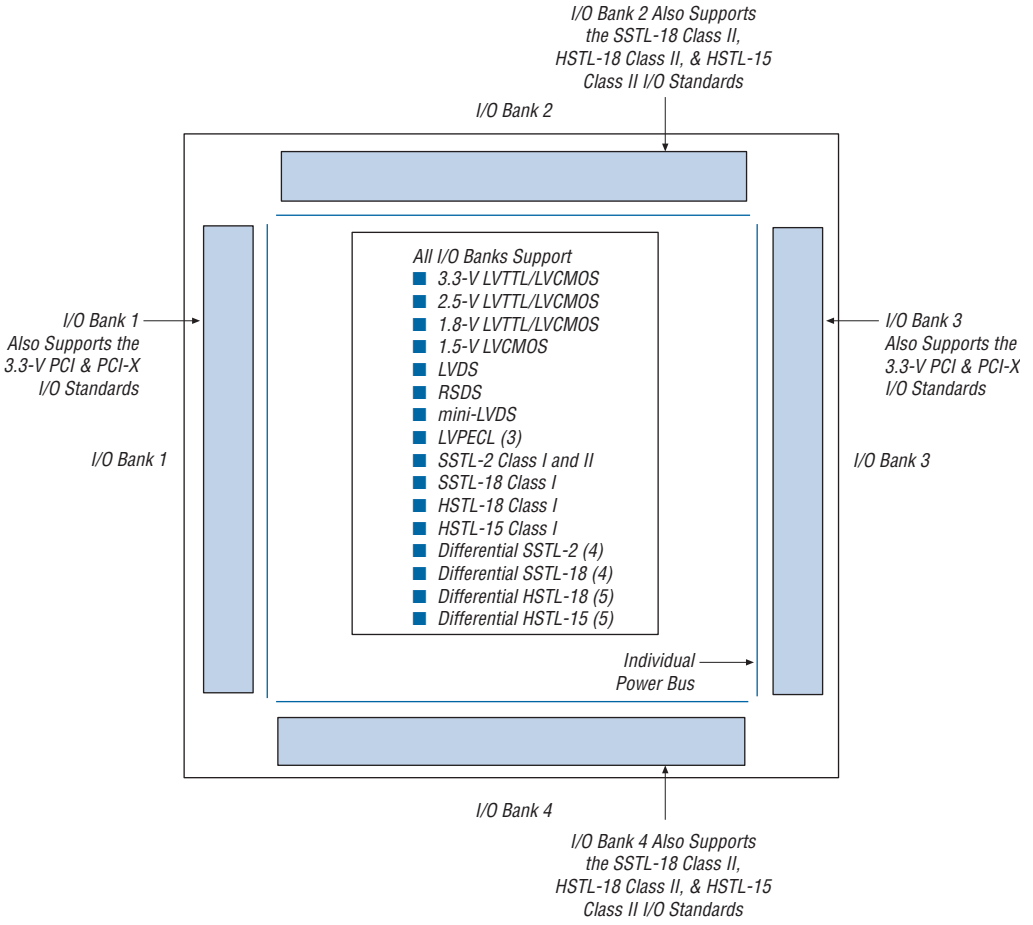
Figure 2–28. EP2C5 & EP2C8 I/O Banks *Notes (1), (2)*



Notes to Figure 2–28:

(1) This is a top view of the silicon die.
(2) This is a graphic representation only. Refer to the pin list and the Quartus II software for exact pin locations.
(3) The LVPECL I/O standard is only supported on clock input pins. This I/O standard is not supported on output pins.
(4) The differential SSTL-18 and SSTL-2 I/O standards are only supported on clock input pins and PLL output clock pins.
(5) The differential 1.8-V and 1.5-V HSTL I/O standards are only supported on clock input pins and PLL output clock pins.

SRAM configuration elements allow Cyclone II devices to be reconfigured in-circuit by loading new configuration data into the device. With real-time reconfiguration, the device is forced into command mode with the nCONFIG pin. The configuration process loads different configuration data, reinitializes the device, and resumes user-mode operation. You can perform in-field upgrades by distributing new configuration files within the system or remotely.

A built-in weak pull-up resistor pulls all user I/O pins to V_{CCIO} before and during device configuration.

The configuration pins support 1.5-V/1.8-V or 2.5-V/3.3-V I/O standards. The voltage level of the configuration output pins is determined by the V_{CCIO} of the bank where the pins reside. The bank V_{CCIO} selects whether the configuration inputs are 1.5-V, 1.8-V, 2.5-V, or 3.3-V compatible.

Configuration Schemes

You can load the configuration data for a Cyclone II device with one of three configuration schemes (see Table 3–4), chosen on the basis of the target application. You can use a configuration device, intelligent controller, or the JTAG port to configure a Cyclone II device. A low-cost configuration device can automatically configure a Cyclone II device at system power-up.

Multiple Cyclone II devices can be configured in any of the three configuration schemes by connecting the configuration enable (nCE) and configuration enable output (nCEO) pins on each device.

Table 3–4. Data Sources for Configuration

Configuration Scheme	Data Source
Active serial (AS)	Low-cost serial configuration device
Passive serial (PS)	Enhanced or EPC2 configuration device, MasterBlaster, ByteBlasterMV, ByteBlaster II or USB Blaster download cable, or serial data source
JTAG	MasterBlaster, ByteBlasterMV, ByteBlaster II or USB Blaster download cable or a microprocessor with a Jam or JBC file

For more information on configuration, see the *Configuring Cyclone II Devices* chapter of the *Cyclone II Handbook, Volume 2*.

Table 5–7. DC Characteristics of User I/O Pins Using Single-Ended Standards Notes (1), (2) **(Part 2 of 2)**

I/O Standard	Test Conditions		Voltage Thresholds	
	I_{OL} (mA)	I_{OH} (mA)	Maximum V_{OL} (V)	Minimum V_{OH} (V)
1.5-V HSTL class I	8	–8	0.4	V_{CCIO} – 0.4
1.5V HSTL class II	16	–16	0.4	V_{CCIO} – 0.4

Notes to Table 5–7:

(1) The values in this table are based on the conditions listed in Tables 5–2 and 5–6.

(2) This specification is supported across all the programmable drive settings available as shown in the *Cyclone II Architecture* chapter of the *Cyclone II Device Handbook*.

Differential I/O Standards

The RSDS and mini-LVDS I/O standards are only supported on output pins. The LVDS I/O standard is supported on both receiver input pins and transmitter output pins.

For more information on how these differential I/O standards are implemented, refer to the *High-Speed Differential Interfaces in Cyclone II Devices* chapter of the *Cyclone II Device Handbook*.

Figure 5–1 shows the receiver input waveforms for all differential I/O standards (LVDS, LVPECL, differential 1.5-V HSTL class I and II, differential 1.8-V HSTL class I and II, differential SSTL-2 class I and II, and differential SSTL-18 class I and II).

Table 5–16. LE_FF Internal Timing Microparameters (Part 2 of 2)

Parameter	–6 Speed Grade (1)		–7 Speed Grade (2)		–8 Speed Grade (3)		Unit
	Min	Max	Min	Max	Min	Max	
TPRE	191	—	244	—	244	—	ps
	—	—	217	—	244	—	ps
TCLKL	1000	—	1242	—	1242	—	ps
	—	—	1111	—	1242	—	ps
TCLKH	1000	—	1242	—	1242	—	ps
	—	—	1111	—	1242	—	ps
tLUT	180	438	172	545	172	651	ps
	—	—	180	—	180	—	ps

Notes to Table 5–16:

(1) For the –6 speed grades, the minimum timing is for the commercial temperature grade. The –7 speed grade devices offer the automotive temperature grade. The –8 speed grade devices offer the industrial temperature grade.

(2) For each parameter of the –7 speed grade columns, the value in the first row represents the minimum timing parameter for automotive devices. The second row represents the minimum timing parameter for commercial devices.

(3) For each parameter of the –8 speed grade columns, the value in the first row represents the minimum timing parameter for industrial devices. The second row represents the minimum timing parameter for commercial devices.

Table 5–17. IOE Internal Timing Microparameters (Part 1 of 2)

Parameter	–6 Speed Grade (1)		–7 Speed Grade (2)		–8 Speed Grade (3)		Unit
	Min	Max	Min	Max	Min	Max	
TSU	76	—	101	—	101	—	ps
	—	—	89	—	101	—	ps
TH	88	—	106	—	106	—	ps
	—	—	97	—	106	—	ps
TCO	99	155	95	171	95	187	ps
	—	—	99	—	99	—	ps
TPIN2COMBOUT_R	384	762	366	784	366	855	ps
	—	—	384	—	384	—	ps
TPIN2COMBOUT_C	385	760	367	783	367	854	ps
	—	—	385	—	385	—	ps
TCOMBIN2PIN_R	1344	2490	1280	2689	1280	2887	ps
	—	—	1344	—	1344	—	ps

Table 5–25. EP2C15A Column Pins Global Clock Timing Parameters

Parameter	Fast Corner		–6 Speed Grade	–7 Speed Grade (1)	–7 Speed Grade (2)	–8 Speed Grade	Unit
	Industrial/ Automotive	Commercial					
$t_{PLLCOUT}$	–0.337	–0.357	0.079	0.04	0.075	0.045	ns

Notes to Table 5–25:
(1) These numbers are for commercial devices.
(2) These numbers are for automotive devices.

Table 5–26. EP2C15A Row Pins Global Clock Timing Parameters

Parameter	Fast Corner		–6 Speed Grade	–7 Speed Grade (1)	–7 Speed Grade (2)	–8 Speed Grade	Unit
	Industrial/ Automotive	Commercial					
t_{CIN}	1.542	1.615	2.490	2.651	2.886	2.866	ns
t_{COUT}	1.544	1.617	2.506	2.664	2.894	2.874	ns
t_{PLLCIN}	–0.424	–0.448	–0.057	–0.107	–0.077	–0.107	ns
$t_{PLLCOUT}$	–0.422	–0.446	–0.041	–0.094	–0.069	–0.099	ns

Notes to Table 5–26:
(1) These numbers are for commercial devices.
(2) These numbers are for automotive devices.

EP2C20/A Clock Timing Parameters

Tables 5–27 and 5–28 show the clock timing parameters for EP2C20/A devices.

Table 5–27. EP2C20/A Column Pins Global Clock Timing Parameters (Part 1 of 2)

Parameter	Fast Corner		–6 Speed Grade	–7 Speed Grade (1)	–7 Speed Grade (2)	–8 Speed Grade	Unit
	Industrial/ Automotive	Commercial					
t_{CIN}	1.621	1.698	2.590	2.766	3.009	2.989	ns
t_{COUT}	1.635	1.713	2.624	2.798	3.038	3.018	ns
t_{PLLCIN}	–0.351	–0.372	0.045	0.008	0.046	0.016	ns

Table 5–45. Maximum Output Clock Toggle Rate on Cyclone II Devices (Part 2 of 4)

I/O Standard	Drive Strength	Maximum Output Clock Toggle Rate on Cyclone II Devices (MHz)								
		Column I/O Pins *(1)*			Row I/O Pins *(1)*			Dedicated Clock Outputs		
		–6 Speed Grade	–7 Speed Grade	–8 Speed Grade	–6 Speed Grade	–7 Speed Grade	–8 Speed Grade	–6 Speed Grade	–7 Speed Grade	–8 Speed Grade
LVCMOS	4 mA	250	210	170	250	210	170	250	210	170
	8 mA	280	230	190	280	230	190	280	230	190
	12 mA	310	260	210	310	260	210	310	260	210
	16 mA	320	270	220	—	—	—	—	—	—
	20 mA	350	290	240	—	—	—	—	—	—
	24 mA	370	310	250	—	—	—	—	—	—
2.5V	4 mA	180	150	120	180	150	120	180	150	120
	8 mA	280	230	190	280	230	190	280	230	190
	12 mA	440	370	300	—	—	—	—	—	—
	16 mA	450	405	350	—	—	—	—	—	—
1.8V	2 mA	120	100	80	120	100	80	120	100	80
	4 mA	180	150	120	180	150	120	180	150	120
	6 mA	220	180	150	220	180	150	220	180	150
	8 mA	240	200	160	240	200	160	240	200	160
	10 mA	300	250	210	300	250	210	300	250	210
	12 mA	350	290	240	350	290	240	350	290	240
1.5V	2 mA	80	60	50	80	60	50	80	60	50
	4 mA	130	110	90	130	110	90	130	110	90
	6 mA	180	150	120	180	150	120	180	150	120
	8 mA	230	190	160	—	—	—	—	—	—
SSTL_2_CLASS_I	8 mA	400	340	280	400	340	280	400	340	280
	12 mA	400	340	280	400	340	280	400	340	280
SSTL_2_CLASS_II	16 mA	350	290	240	350	290	240	350	290	240
	20 mA	400	340	280	—	—	—	—	—	—
	24 mA	400	340	280	—	—	—	—	—	—
SSTL_18_CLASS_I	6 mA	260	220	180	260	220	180	260	220	180
	8 mA	260	220	180	260	220	180	260	220	180
	10 mA	270	220	180	270	220	180	270	220	180
	12 mA	280	230	190	—	—	—	—	—	—

Table 5–50. LVDS Transmitter Timing Specification (Part 2 of 2)

Symbol	Conditions	–6 Speed Grade				–7 Speed Grade				–8 Speed Grade				Unit
		Min	Typ	Max (1)	Max (2)	Min	Typ	Max (1)	Max (2)	Min	Typ	Max (1)	Max (2)	
t_{FALL}	80–20%	150	200	250		150	200	250		150	200	250 (11)		ps
t_{LOCK}	—	—	—	100		—	—	100		—	—	100 (12)		µs

Notes to Table 5–50:

(1) The maximum data rate that complies with duty cycle distortion of 45–55%.

(2) The maximum data rate when taking duty cycle in absolute ps into consideration that may not comply with 45–55% duty cycle distortion. If the downstream receiver can handle duty cycle distortion beyond the 45–55% range, you may use the higher data rate values from this column. You can calculate the duty cycle distortion as a percentage using the absolute ps value. For example, for a data rate of 640 Mbps (UI = 1562.5 ps) and a t_{DUTY} of 250 ps, the duty cycle distortion is ± t_{DUTY} / (UI*2) *100% = ± 250 ps / (1562.5 *2) * 100% = ± 8%, which gives you a duty cycle distortion of 42–58%.

(3) The TCCS specification applies to the entire bank of LVDS, as long as the SERDES logic is placed within the LAB adjacent to the output pins.

(4) For extended temperature devices, the maximum input clock frequency for ×10 through ×2 modes is 137.5 MHz.

(5) For extended temperature devices, the maximum data rate for ×10 through ×2 modes is 275 Mbps.

(6) For extended temperature devices, the maximum input clock frequency for ×10 through ×2 modes is 200 MHz.

(7) For extended temperature devices, the maximum data rate for ×10 through ×2 modes is 400 Mbps.

(8) For extended temperature devices, the maximum input clock frequency for ×1 mode is 340 MHz.

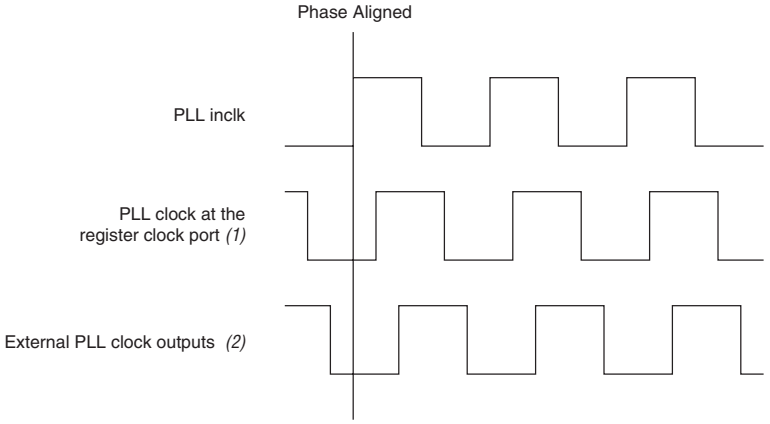
(9) For extended temperature devices, the maximum data rate for ×1 mode is 340 Mbps.

(10) For extended temperature devices, the maximum output jitter (peak to peak) is 600 ps.

(11) For extended temperature devices, the maximum t_{RISE} and t_{FALL} are 300 ps.

(12) For extended temperature devices, the maximum lock time is 500 us.

Figure 7–6. Phase Relationship between Cyclone II PLL Clocks in No Compensation Mode



Notes to Figure 7–6:
(1) Internal clocks fed by the PLL are in phase with each other.
(2) The external clock outputs can lead or lag the PLL internal clocks.

Source-Synchronous Mode

If data and clock arrive at the same time at the input pins, they are guaranteed to keep the same phase relationship at the clock and data ports of any IOE input register. Figure 7–7 shows an example waveform of the clock and data in this mode. This mode is recommended for source-synchronous data transfer. Data and clock signals at the IOE experience similar buffer delays as long as the same I/O standard is used.

Table 7–9. Clock Control Block Inputs (Part 2 of 2)

Input	Description
PLL outputs	The PLL counter outputs can drive the global clock network.
Internal logic	The global clock network can also be driven through the logic array routing to enable internal logic (LEs) to drive a high fan-out, low skew signal path.

In Cyclone II devices, the dedicated clock input pins, PLL counter outputs, dual-purpose clock I/O inputs, and internal logic can all feed the clock control block for each global clock network. The output from the clock control block in turn feeds the corresponding global clock network. The clock control blocks are arranged on the device periphery and there are a maximum of 16 clock control blocks available per Cyclone II device.

The control block has two functions:

- Dynamic global clock network clock source selection
- Global clock network power-down (dynamic enable and disable)

Figure 7–11 shows the clock control block.

ROM Mode

Cyclone II memory blocks support ROM mode. A MIF initializes the ROM contents of these blocks. The address lines of the ROM are registered. The outputs can be registered or unregistered. The ROM read operation is identical to the read operation in the single-port RAM configuration.

FIFO Buffer Mode

A single clock or dual clock FIFO buffer may be implemented in the memory blocks. Dual clock FIFO buffers are useful when transferring data from one clock domain to another clock domain. All FIFO memory configurations have synchronous inputs. However, the FIFO buffer outputs are always combinational (i.e., not registered). Simultaneous read and write from an empty FIFO buffer is not supported.

For more information on FIFO buffers, refer to the *Single- & Dual-Clock FIFO Megafunctions User Guide*.

Clock Modes

Depending on which memory mode is selected, the following clock modes are available:

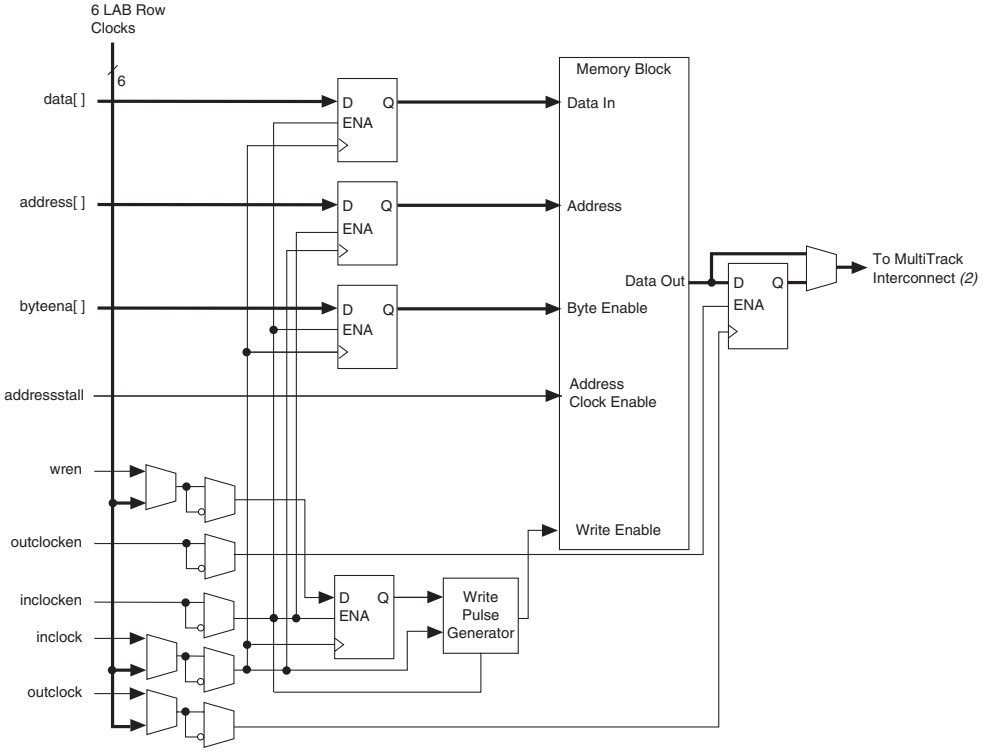
- Independent
- Input/output
- Read/write
- Single-clock

Table 8–7 shows these clock modes supported by all memory blocks when configured in each respective memory modes.

Table 8–7. Cyclone II Memory Clock Modes

Clocking Modes	True Dual-Port Mode	Simple Dual-Port Mode	Single-Port Mode
Independent	✓		
Input/output	✓	✓	✓
Read/write		✓	
Single clock	✓	✓	✓

Figure 8–16. Cyclone II Input/Output Clock Mode in Single-Port Mode *Notes (1), (2)*



Notes to Figure 8–16:

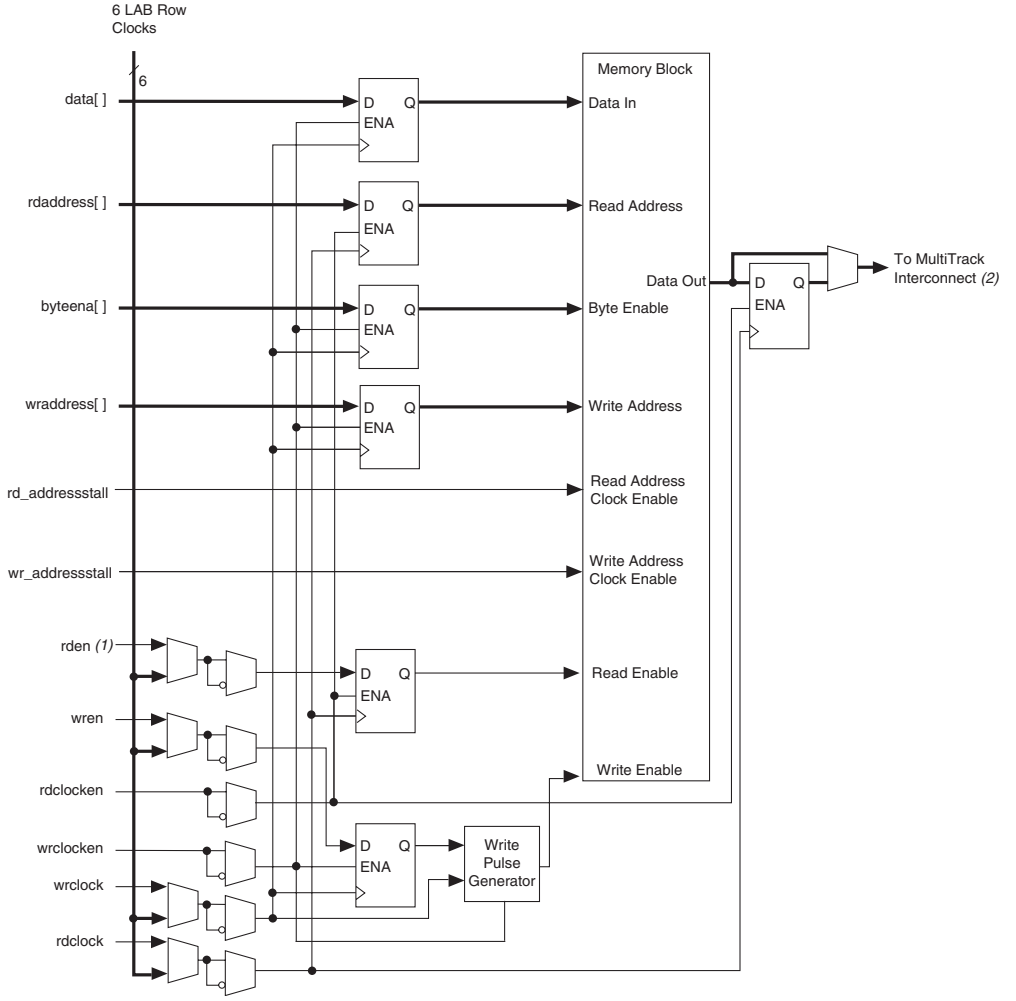
(1) Violating the setup or hold time on the memory block address registers could corrupt memory contents. This applies to both read and write operations.

(2) For more information about the MultiTrack interconnect, refer to *Cyclone II Device Family Data Sheet* in volume 1 of the *Cyclone II Device Handbook*.

Read/Write Clock Mode

Cyclone II memory blocks can implement read/write clock mode for simple dual-port memory. The write clock controls the blocks' data inputs, write address, and write enable signals. The read clock controls the data output, read address, and read enable signals. The memory blocks support independent clock enables for each clock for the read- and write-side registers. This mode does not support asynchronous clear signals for the registers. Figure 8–17 shows a memory block in read/write clock mode.

Figure 8–17. Cyclone II Read/Write Clock Mode *Notes (1), (2)*



Notes to Figure 8–17:

(1) Violating the setup or hold time on the memory block address registers could corrupt memory contents. This applies to both read and write operations.

(2) For more information about the MultiTract interconnect, refer to *Cyclone II Device Family Data Sheet* in volume 1 of the *Cyclone II Device Handbook*.

QDRII SRAM devices use the following clock signals:

- Input clocks K and K#
- Optional output clocks C and C#
- Echo clocks CQ and CQn

Clocks C#, K#, and CQn are logical complements of clocks C, K, and CQ, respectively. Clocks C, C#, K, and K# are inputs to the QDRII SRAM, and clocks CQ and CQn are outputs from the QDRII SRAM. Cyclone II devices use single-clock mode for QDRII SRAM interfacing. The K and K# clocks are used for both read and write operations, and the C and C# clocks are unused.

You can generate C, C#, K, and K# clocks using any of the I/O registers via the DDR registers. Due to strict skew requirements between K and K# signals, use adjacent pins to generate the clock pair. Surround the pair with buffer pins tied to V_{CC} and pins tied to ground for better noise immunity from other signals.

In Cyclone II devices, another DQS pin implements the CQn pin in the QDRII SRAM memory interface. These pins are denoted by DQS/CQ# in the pin table. Connect CQ and CQn pins to the Cyclone II DQS/CQ and DQS/CQ# pins of the same DQ groups, respectively. You must configure the DQS/CQ and DQS/CQ# as bidirectional pins. However, because CQ and CQn pins are output-only pins from the memory device, the Cyclone II device's QDRII SRAM memory interface requires that you ground the DQS/CQ and DQS/CQ# output enable. To capture data presented by the memory device, connect the shifted CQ signal to register C_I and input register A_I. Connect the shifted CQn to input register B_I. Figure 9–4 shows the CQ and CQn connections for a QDRII SRAM read.

Table 10–2. Cyclone II 66-MHz PCI Support (Part 2 of 2)

Device	Package	–6 and –7 Speed Grades	
		64 Bits	32 Bits
EP2C8	144-pin TQFP		
	208-pin PQFP		✓
	256-pin FineLine BGA		✓
EP2C15	256-pin FineLine BGA		✓
	484-pin FineLine BGA	✓	✓
EP2C20	240-pin PQFP		✓
	256-pin FineLine BGA		✓
	484-pin FineLine BGA	✓	✓
EP2C35	484-pin FineLine BGA	✓	✓
	672-pin FineLine BGA	✓	✓
EP2C50	484-pin FineLine BGA	✓	✓
	672-pin FineLine BGA	✓	✓
EP2C70	672-pin FineLine BGA	✓	✓
	896-pin FineLine BGA	✓	✓

Table 10–3 lists the specific Cyclone II devices that support 64-bit and 32-bit PCI at 33 MHz.

Table 10–3. Cyclone II 33-MHz PCI Support (Part 1 of 2)

Device	Package	–6, –7 and –8 Speed Grades	
		64 Bits	32 Bits
EP2C5	144-pin TQFP	—	—
	208-pin PQFP	—	✓
	256-pin FineLine BGA	—	✓
EP2C8	144-pin TQFP	—	—
	208-pin PQFP	—	✓
	256-pin FineLine BGA	—	✓
EP2C15	256-pin FineLine BGA	—	✓
	484-pin FineLine BGA	✓	✓

When the `signa` and `signb` signals are unused, the Quartus® II software sets the multiplier to perform unsigned multiplication by default.

Output Registers

You can choose to register the embedded multiplier output using the output registers in 18- or 36-bit sections depending on the operational mode of the multiplier. The following control signals are available to each output register within the embedded multiplier:

- clock
- clock enable
- asynchronous clear

All input and output registers within a single embedded multiplier are fed by the same clock, clock enable, or asynchronous clear signal.

See the *Cyclone II Architecture* chapter in Volume 1 of the ***Cyclone II Device Handbook*** for more information on the embedded multiplier routing and interface.

Operational Modes

The embedded multiplier can be used in one of two operational modes, depending on the application needs:

- One 18-bit multiplier
- Up to two 9-bit independent multipliers

The Quartus II software includes megafunctions used to control the mode of operation of the multipliers. After you have made the appropriate parameter settings using the megafunction's MegaWizard® Plug-In Manager, the Quartus II software automatically configures the embedded multiplier.

The Cyclone II embedded multipliers can also be used to implement multiplier adder and multiplier accumulator functions where the multiplier portion of the function is implemented using embedded multipliers and the adder or accumulator function is implemented in logic elements (LEs).

For more information on megafunction and Quartus II support for Cyclone II embedded multipliers, see the "Software Support" section.

You should put a buffer before the DATA and DCLK output from the master Cyclone II device to avoid signal strength and signal integrity issues. The buffer should not significantly change the DATA-to-DCLK relationships or delay them with respect to other AS signals (ASDI and nCS). Also, the buffer should only drive the slave Cyclone II devices, so that the timing between the master Cyclone II device and serial configuration device is unaffected.

This configuration method supports both compressed and uncompressed SOFs. Therefore, if the configuration bitstream size exceeds the capacity of a serial configuration device, you can enable the compression feature in the SOF file used or you can select a larger serial configuration device.

Estimating AS Configuration Time

The AS configuration time is the time it takes to transfer data from the serial configuration device to the Cyclone II device. The Cyclone II DCLK output (generated from an internal oscillator) clocks this serial interface. As listed in Table 13–5, if you are using the 40-MHz oscillator, the DCLK minimum frequency is 20 MHz (50 ns). Therefore, the maximum configuration time estimate for an EP2C5 device (1,223,980 bits of uncompressed data) is:

RBF size × (maximum DCLK period / 1 bit per DCLK cycle) = estimated maximum configuration time

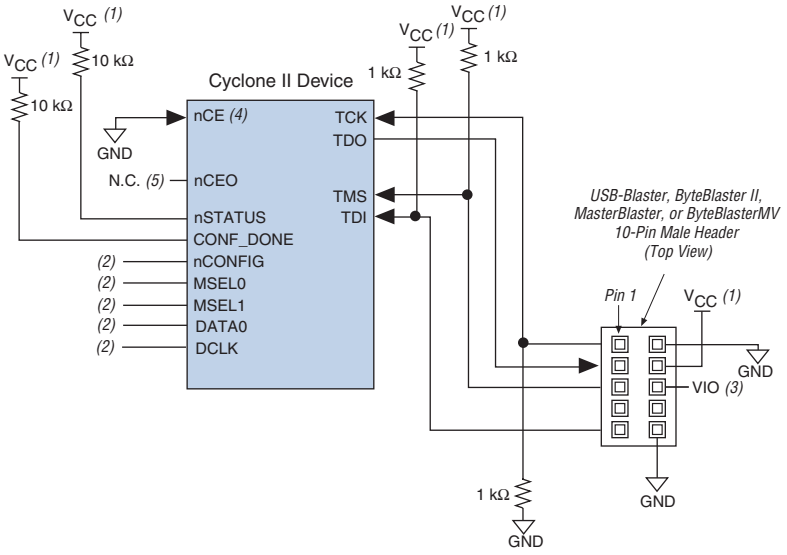
1,223,980 bits × (50 ns / 1 bit) = 61.2 ms

To estimate the typical configuration time, use the typical DCLK period listed in Table 13–5. With a typical DCLK period of 38.46 ns, the typical configuration time is 47.1 ms. Enabling compression reduces the amount of configuration data that is transmitted to the Cyclone II device, which also reduces configuration time. On average, compression reduces configuration time by 50%.

Single Device JTAG Configuration

During JTAG configuration, you can use the USB-Blaster, MasterBlaster, ByteBlaster II, or ByteBlasterMV download cable to download data to the device. Configuring Cyclone II devices through a cable is similar to programming devices in system. Figure 13–22 shows JTAG configuration of a single Cyclone II device using a download cable.

Figure 13–22. JTAG Configuration of a Single Device Using a Download Cable



Notes to Figure 13–22:

(1) The pull-up resistor should be connected to the same supply voltage as the USB-Blaster, MasterBlaster (VIO pin), ByteBlaster II, or ByteBlasterMV cable.

(2) Connect the nCONFIG and MSEL[1..0] pins to support a non-JTAG configuration scheme. If only JTAG configuration is used, connect the nCONFIG pin to V_{CC}, and the MSEL[1..0] pins to ground. In addition, pull DCLK and DATA0 to either high or low, whichever is convenient on your board.

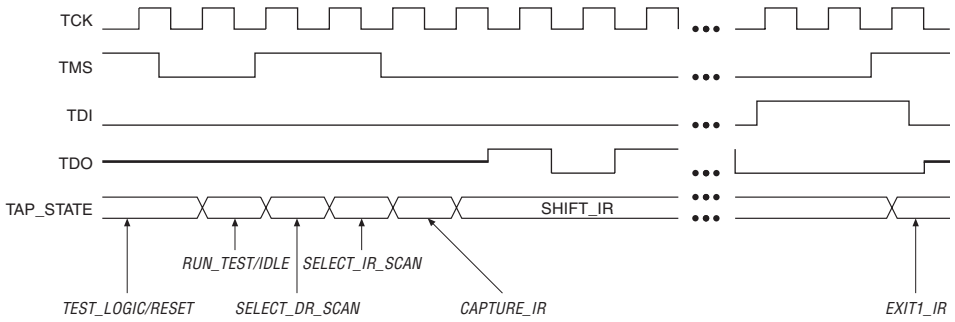
(3) Pin 6 of the header is a V_{IO} reference voltage for the MasterBlaster output driver. V_{IO} should match the device's V_{CCIO}. Refer to the *MasterBlaster Serial/USB Communications Cable Data Sheet* for this value. In the ByteBlasterMV, this pin is a no connect. In the USB-Blaster and ByteBlaster II, this pin is connected to nCE when it is used for AS programming, otherwise it is a no connect.

(4) nCE must be connected to GND or driven low for successful JTAG configuration.

(5) The nCEO pin can be left unconnected or used as a user I/O pin when it does not feed other device's nCE pin.

To configure a single device in a JTAG chain, the programming software places all other devices in BYPASS mode. In BYPASS mode, Cyclone II devices pass programming data from the TDI pin to the TDO pin through a single bypass register without being affected internally. This scheme

Figure 14–7. Selecting the Instruction Mode



The TDO pin is tri-stated in all states except in the SHIFT_IR and SHIFT_DR states. The TDO pin is activated at the first falling edge of TCK after entering either of the shift states and is tri-stated at the first falling edge of TCK after leaving either of the shift states.

When the SHIFT_IR state is activated, TDO is no longer tri-stated, and the initial state of the instruction register is shifted out on the falling edge of TCK. TDO continues to shift out the contents of the instruction register as long as the SHIFT_IR state is active. The TAP controller remains in the SHIFT_IR state as long as TMS remains low.

During the SHIFT_IR state, an instruction code is entered by shifting data on the TDI pin on the rising edge of TCK. The last bit of the instruction code must be clocked at the same time that the next state, EXIT1_IR, is activated. Set TMS high to activate the EXIT1_IR state. Once in the EXIT1_IR state, TDO becomes tri-stated again. TDO is always tri-stated except in the SHIFT_IR and SHIFT_DR states. After an instruction code is entered correctly, the TAP controller advances to serially shift test data in one of seven modes (SAMPLE/PRELOAD, EXTEST, BYPASS, IDCODE, USERCODE, CLAMP, or HIGHZ) that are described below.

SAMPLE/PRELOAD Instruction Mode

The SAMPLE/PRELOAD instruction mode allows you to take a snapshot of device data without interrupting normal device operation. You can also use this instruction to preload the test data into the update registers prior to loading the EXTEST instruction. Figure 14–8 shows the capture, shift, and update phases of the SAMPLE/PRELOAD mode.